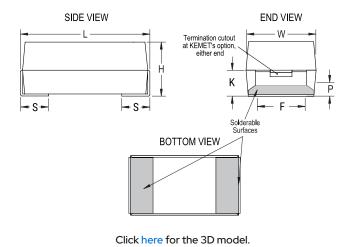


T497H475K050BH6410

T497 HRA, Tantalum, MnO2 Tantalum, HRA, 4.7 uF, 10%, 50 VDC, SMD, MnO2, Molded, High Reliability, Medical, B (0.1%/1000 Hrs), 1.5 Ohms, 7238, 3.17 mm, 1.27 mm



General Information	
Series	T497 HRA
Dielectric	MnO2 Tantalum
Style	SMD Chip
Description	SMD, MnO2, Molded, High Reliability, Medical
Features	High Reliability, Medical
RoHS	No
Prop 65	WARNING: Cancer and reproductive harm - https://www.p65warnings.ca.gov /
SCIP Number	1dd2e1b8-26dd-4d52-927c-6f9 d519011aa
Termination	Tin Lead (SnPb)
Qualifications	CWR09/19/29 Style
AEC-Q200	No
Typical Component Weight	349.01 mg
Notes	Note: When solder coated terminations are required, add an additional 0.38mm (0.015inch) to the tolerances for "L", "W", "H", "K", "F" and "S".
MSL	1

Dimensions	
L	7.24mm +/-0.38mm
W	3.81mm +/-0.38mm
Н	2.79mm +/-0.38mm
S	1.27mm +0.25/-0.13mm
F	3.68mm +0.13/-0.51mm
K	1.52mm MIN
Р	0.76mm MIN
Packaging Specifications	
Packaging	T&R, 178mm

500

Packaging Quantity

Specifications	
Capacitance	4.7 uF
Tolerance	10%
Voltage DC	50 VDC (85C), 33.5 VDC (125C)
Temperature Range	-55/+125°C
Rated Temperature	85°C
Humidity	85C, 85% RH, 1000 Hours, No Load
Dissipation Factor	6% 120Hz 25C
Failure Rate	B (0.1%/1000 Hrs)
ESR	1.5 Ohms (100kHz 25C)
Ripple Current	316 mA (rms, 100kHz 25C)
Leakage Current	2.4 uA (5min 25°C)
Testing and Reliability	10 Cycles Surge Current Testing At -55C And +85C

Statements of suitability for certain applications are based on our knowledge of typical operating conditions for such applications, but are not intended to constitute - and we specifically disclaim - any warranty concerning suitability for a specific customer application or use. This Information is intended for use only by customers who have the requisite experience and capability to determine the correct products for their application. Any technical advice inferred from this Information or otherwise provided by us with reference to the use of our products is given gratis, and we assume no obligation or liability for the advice given or results obtained.

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